



FIG. 1

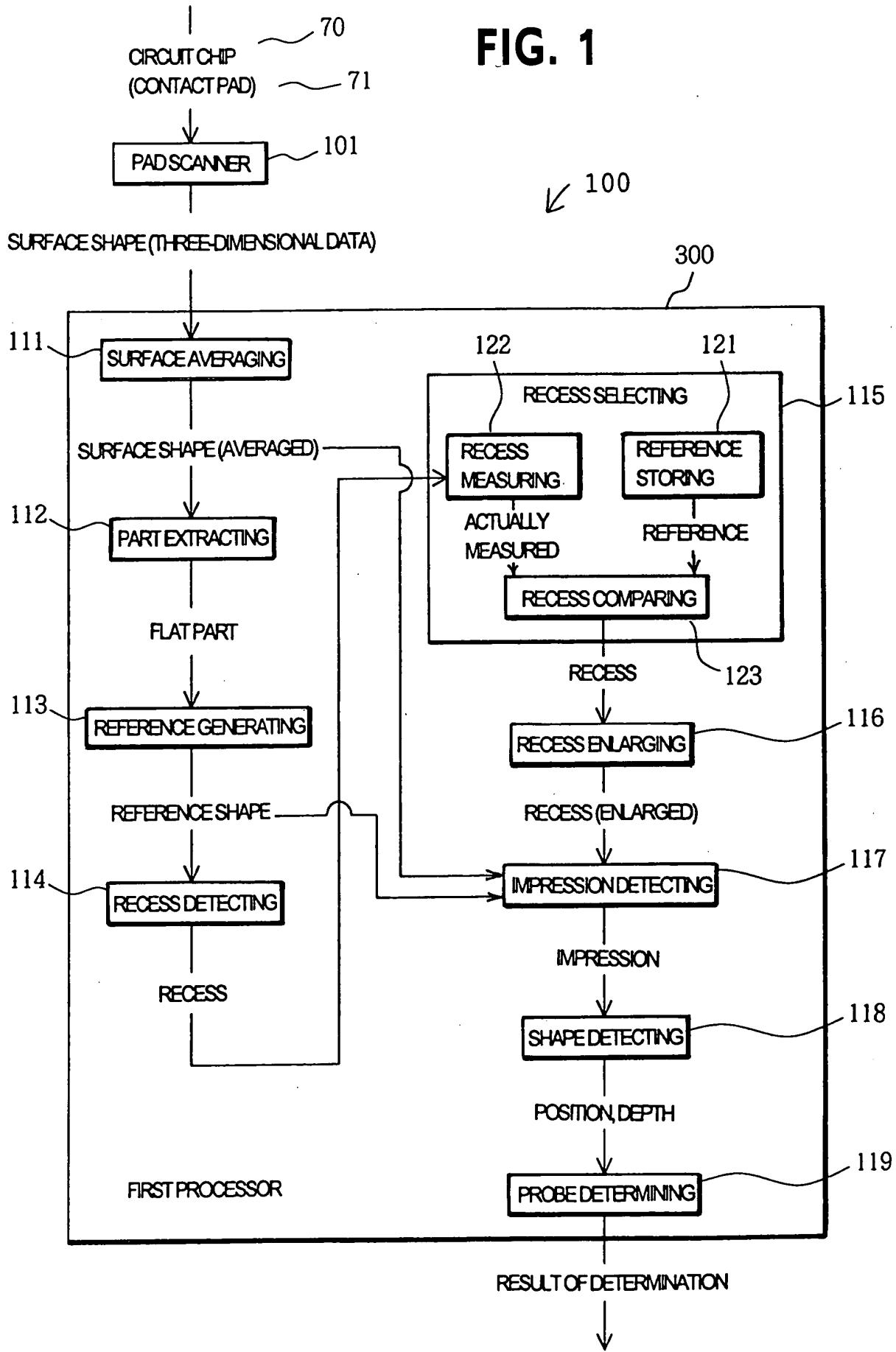




FIG. 2

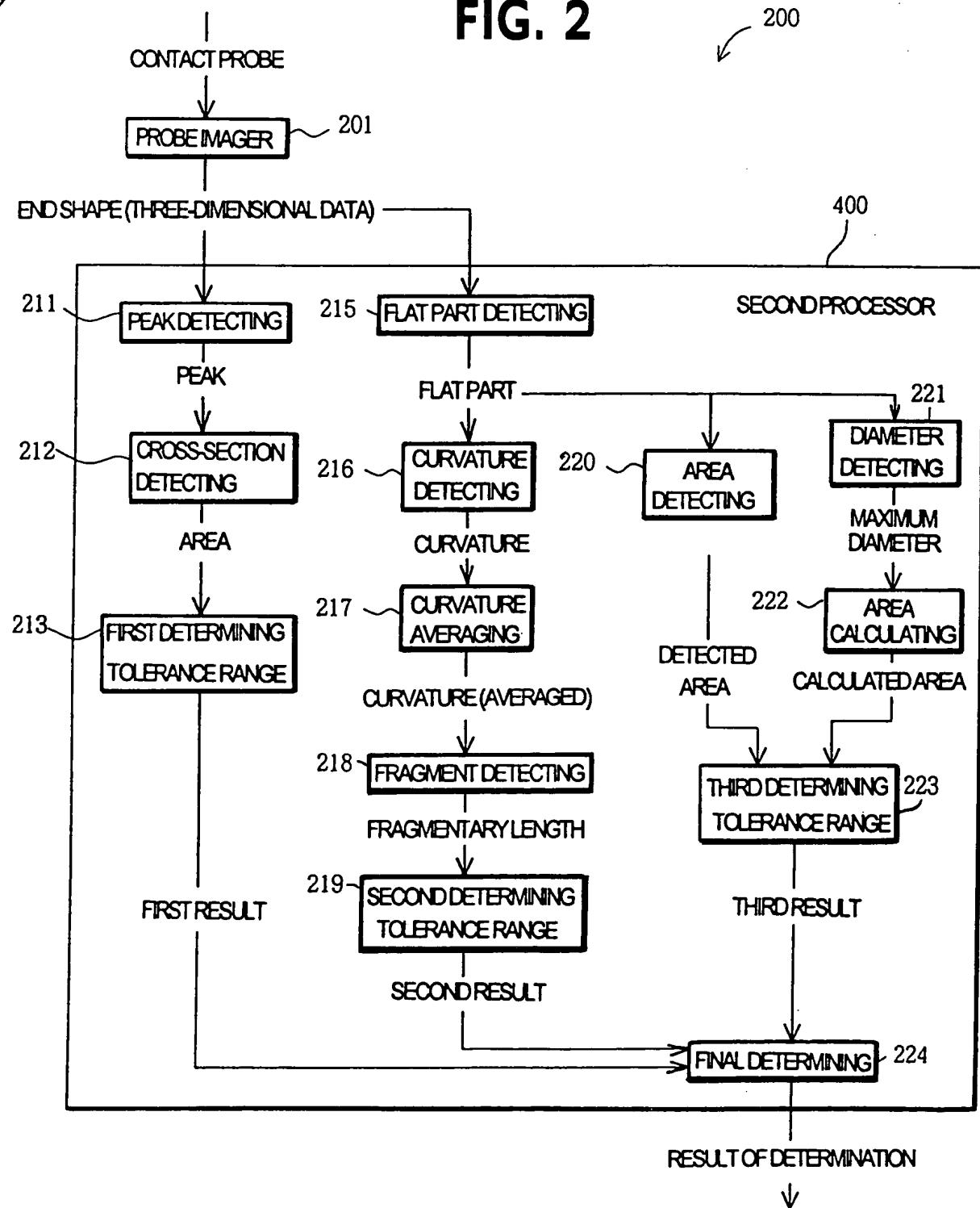




FIG. 3

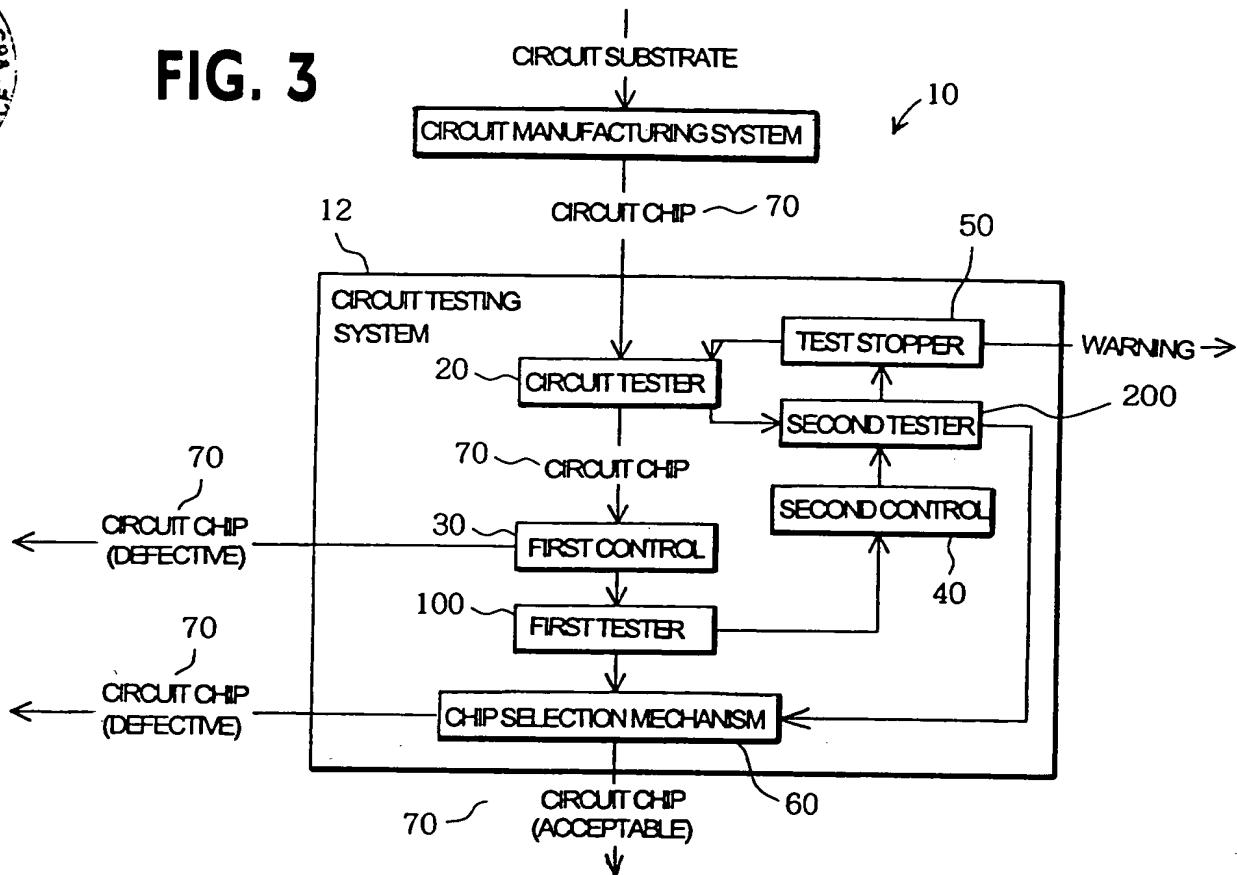


FIG. 4

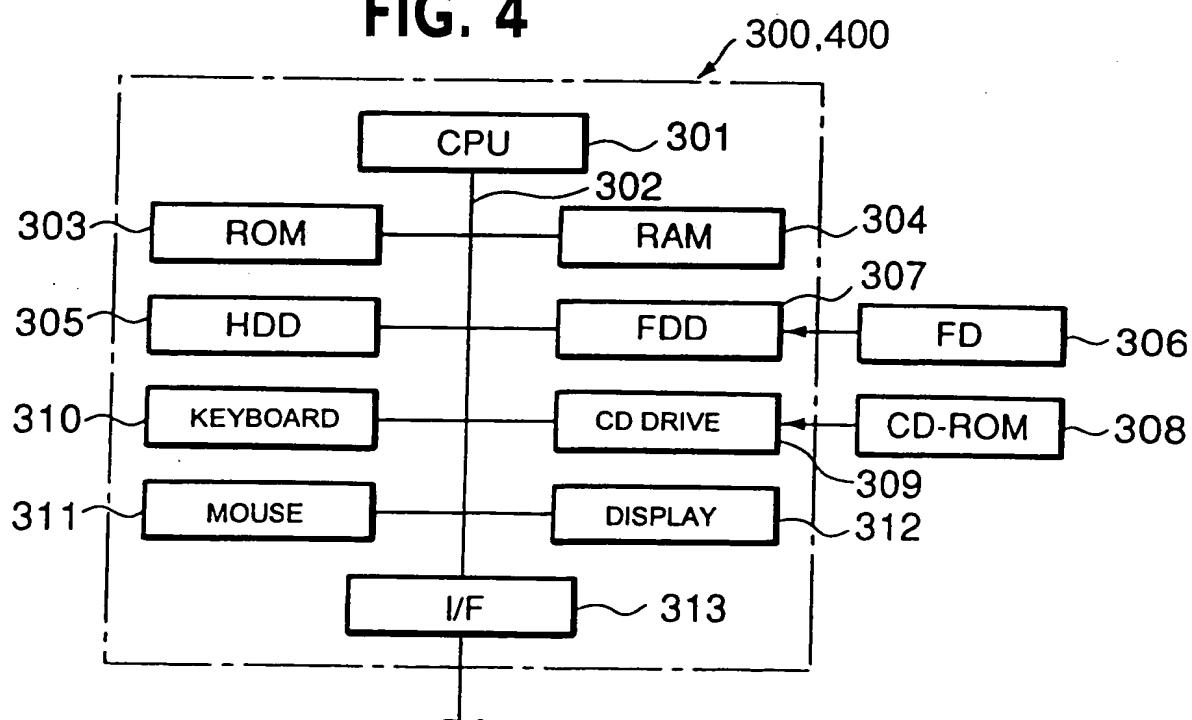




FIG. 5a

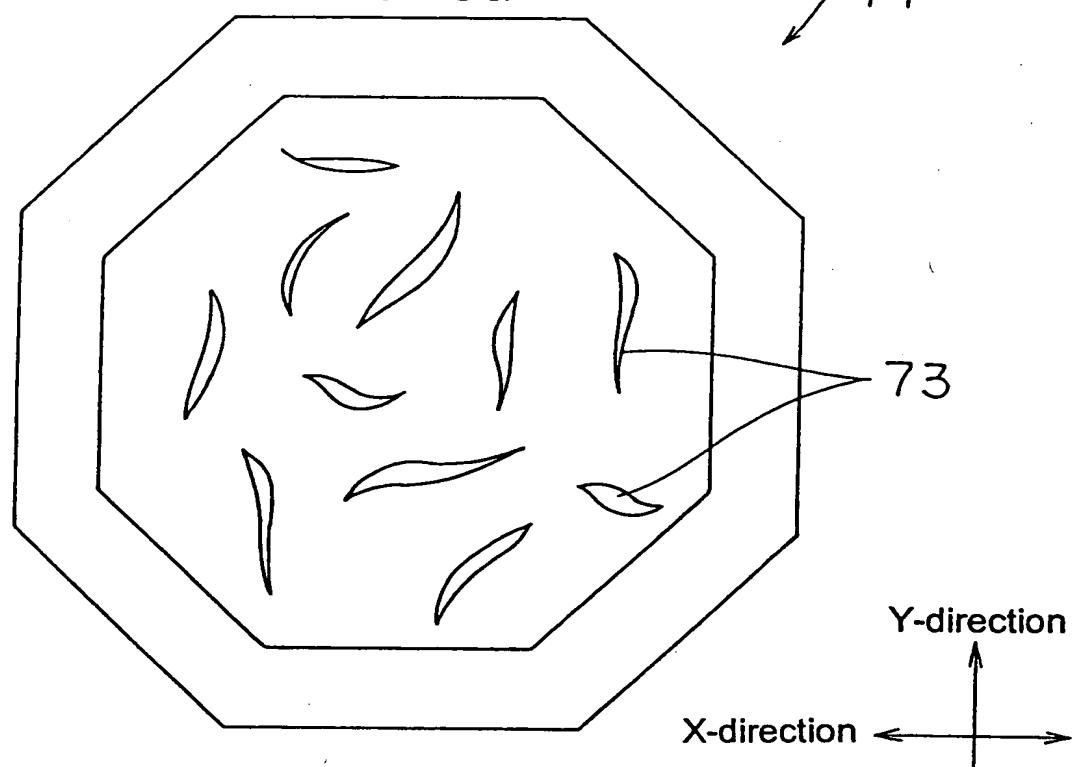
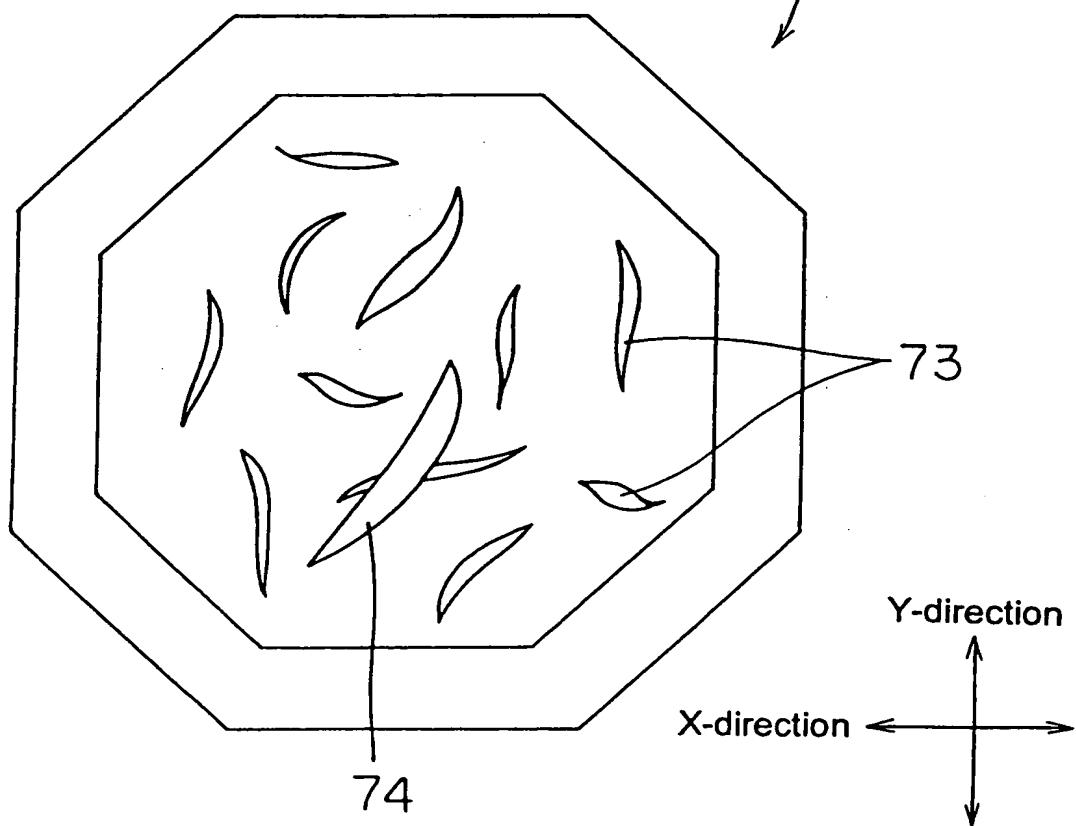


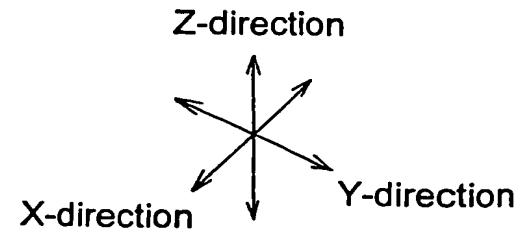
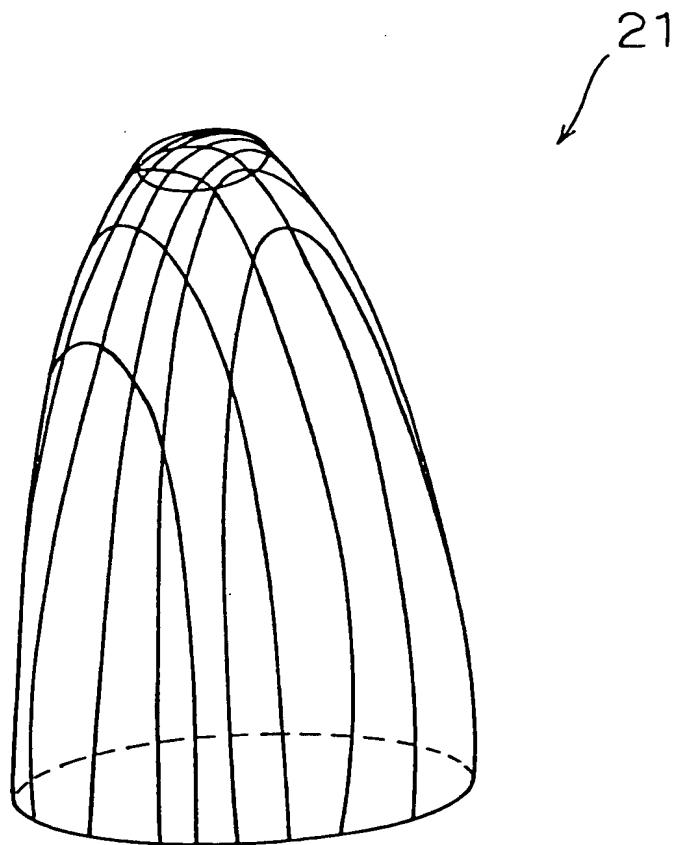
FIG. 5b



Title: PROBE TESTING METHOD AND
APPARATUS FOR DETERMINING
ACCEPTABLE/DEFECTIVE END SHAPE OF
CONTACT PROBE THROUGH IMAGE
ANALYSIS
Inventor(s): Yoshihiro SASAKI, et al.
Appl. No.: 10/644,071



FIG. 6



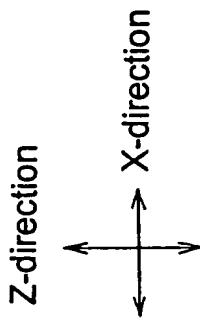


FIG. 7a



FIG. 7b



FIG. 7c



FIG. 7d



~ ~ ~ ~ ~

FIG. 7e

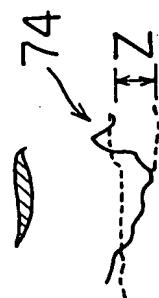


FIG. 7f

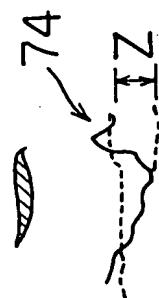


FIG. 7g



FIG. 8a

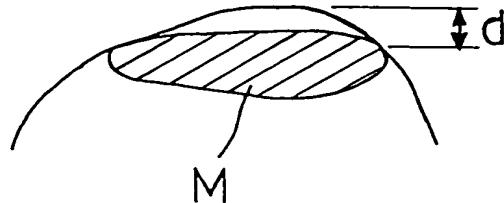


FIG. 8b

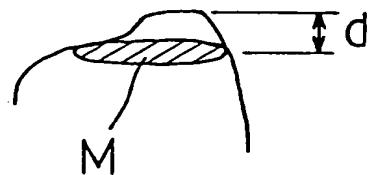


FIG. 9a

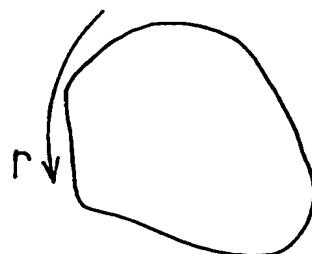


FIG. 9b

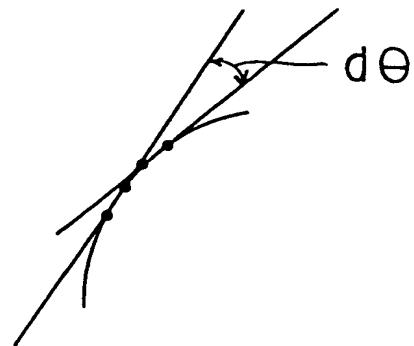


FIG. 9c

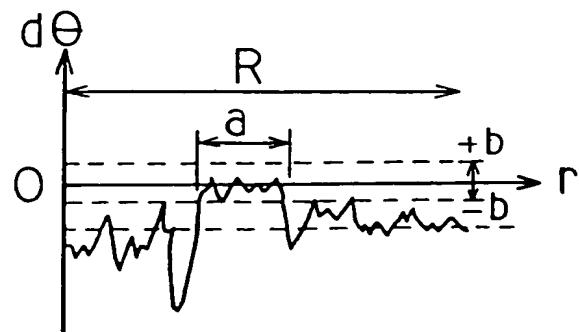




FIG. 10

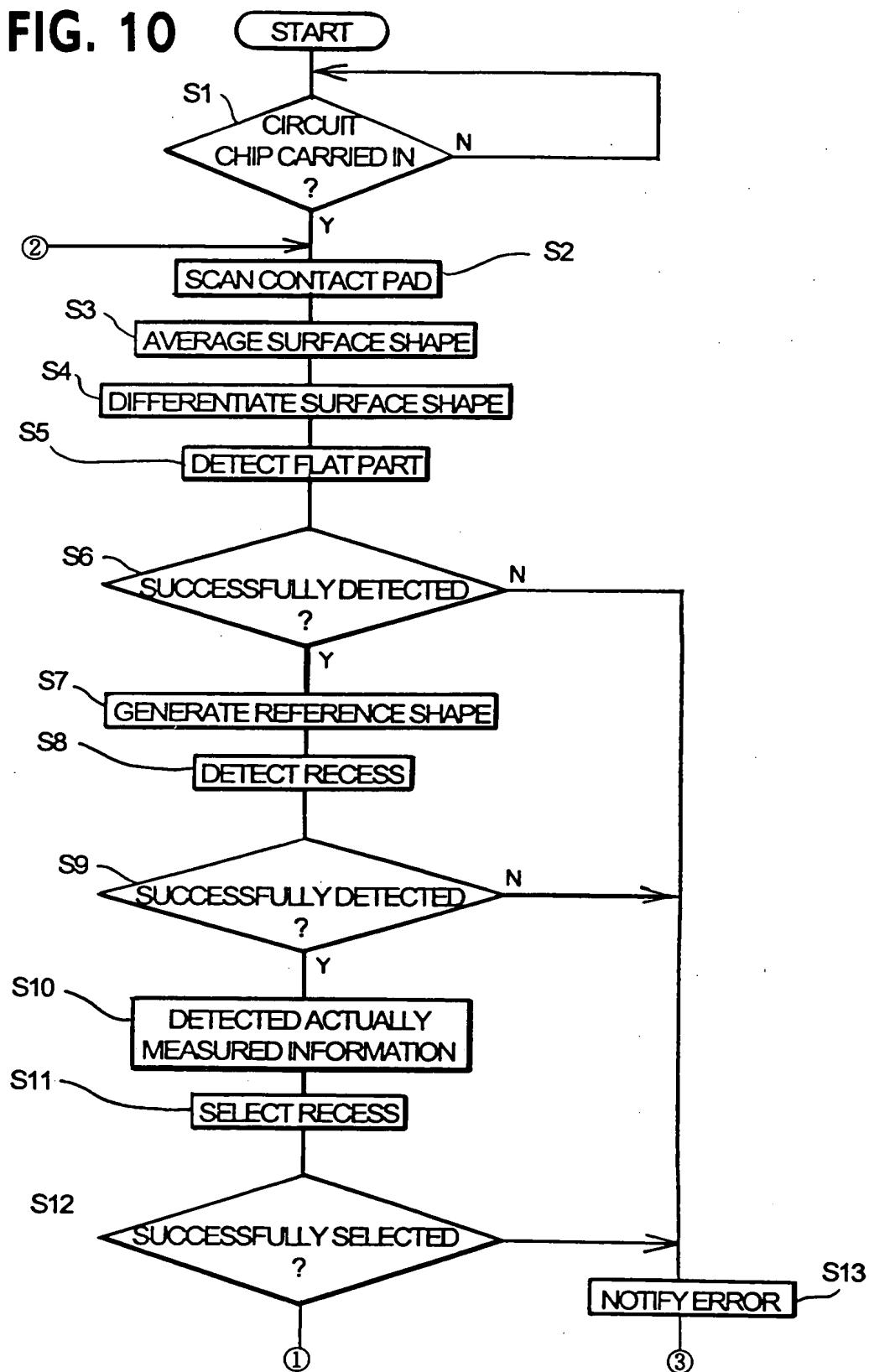




FIG. 11

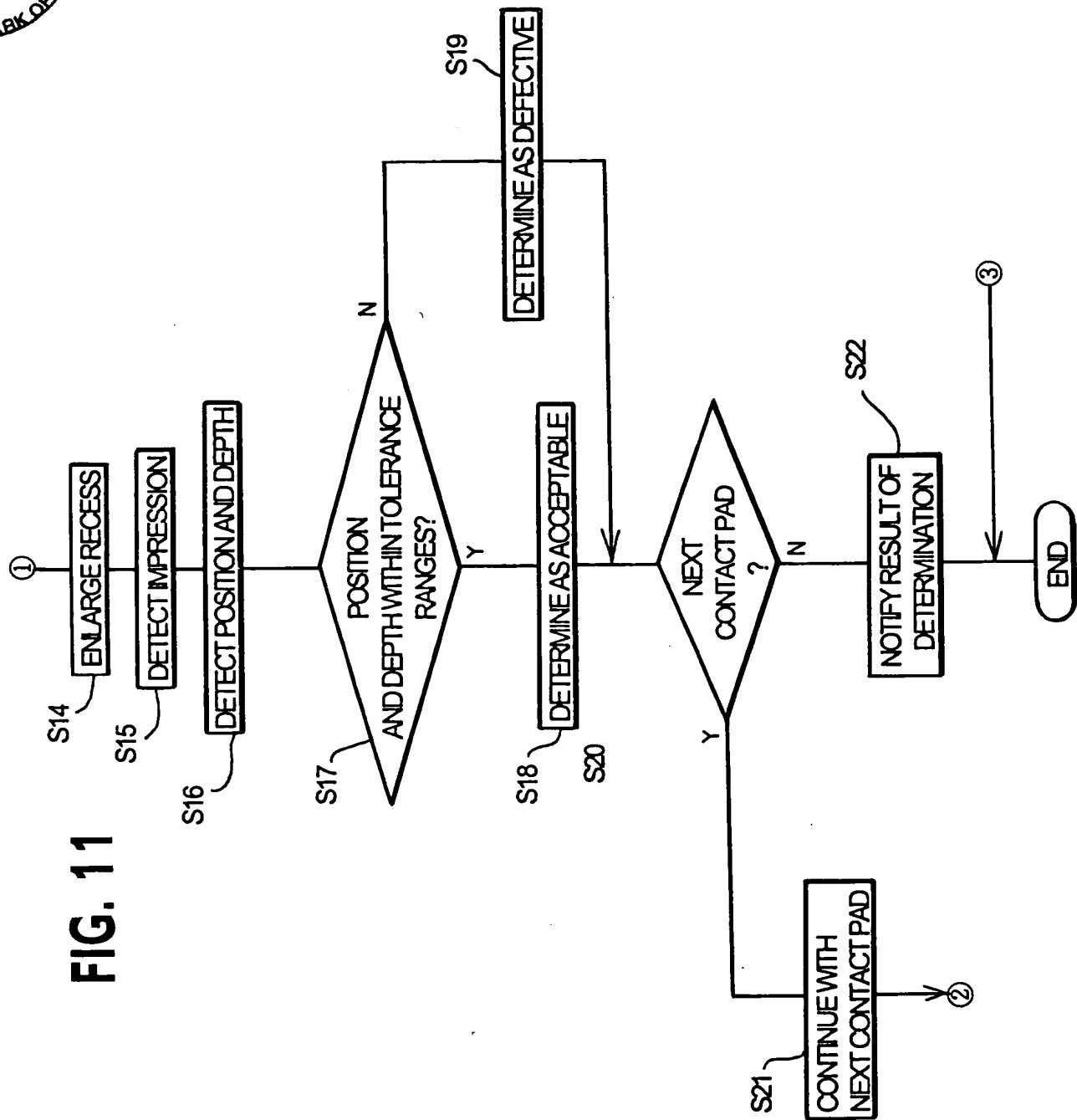




FIG. 12

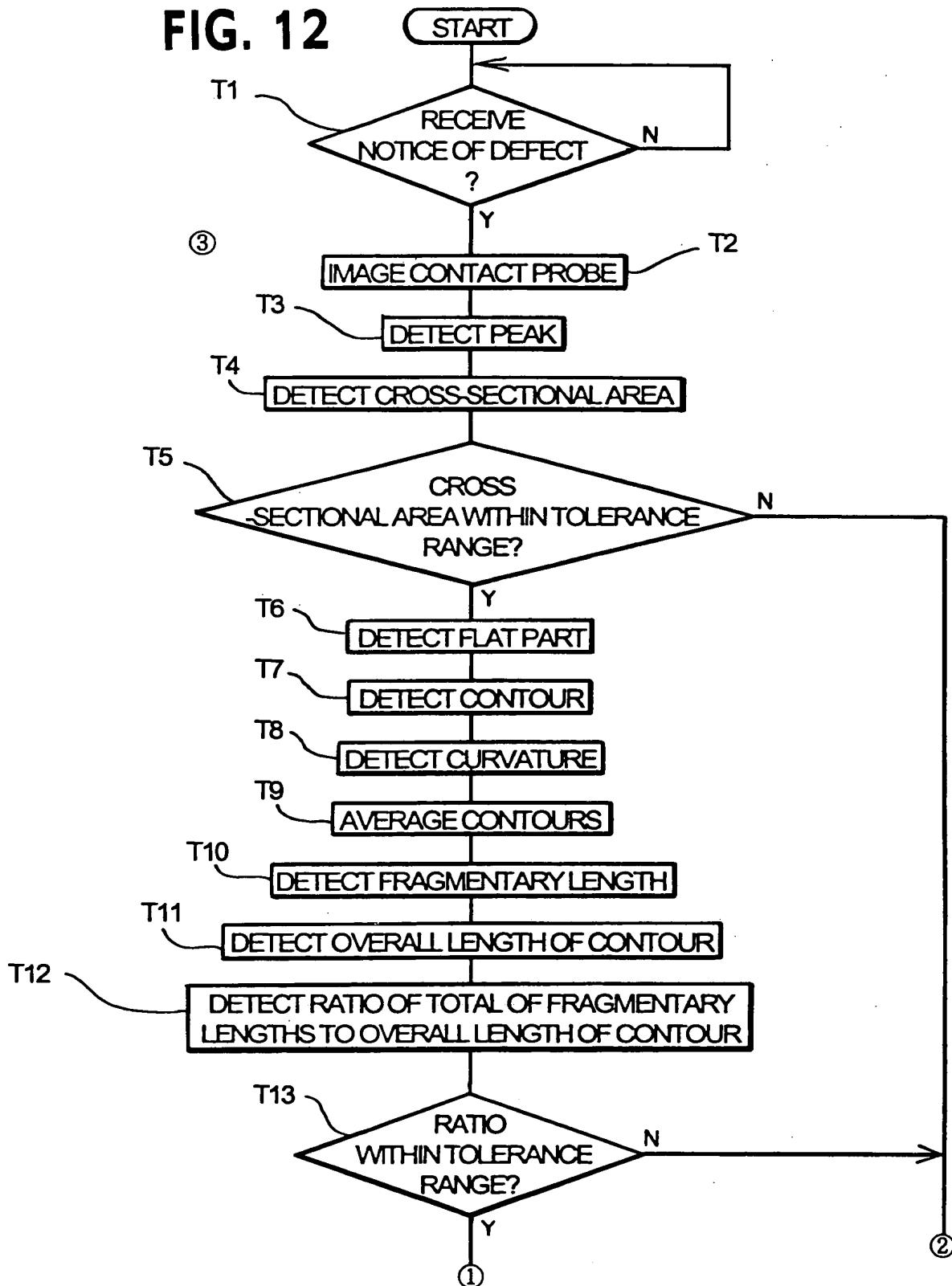




FIG. 13

